

●General Description

It combines trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. It combines one N-channel MOSFET and one P-channel MOSFET.

●Features

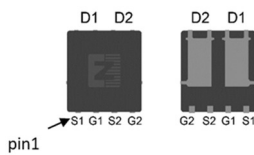
- Low $R_{DS(ON)}$ to minimize conductive loss
- Dual die in one package
- Low thermal resistance
- AEC-Q101 qualified

●Application

- BLDC motor driver
- Load switch



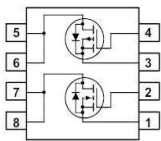
●Product Summary



DFN5*6

●Ordering Information

Part NO.	ZMCA88408N
Marking	ZMC88408
Packing information	REEL TAPE
Basic ordering unit (pcs)	3000



$V_{DS1}=40V$

$V_{DS2}=-40V$

$R_{DS(ON)1}=6.4mR$

$R_{DS(ON)2}=10.4mR$

$I_{D1}=64A$

$I_{D2}=-61A$



●N-Channel Absolute Maximum Ratings ($T_A=25^{\circ}C$, unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Max.	Unit
Drain-source voltage	V_{DS}		-	40	V
Gate-source voltage ^①	V_{GS}		-20	20	V
Continuous drain current	I_D	$V_{GS}=10V, T_C=25^{\circ}C$	-	64	A
	I_D	$V_{GS}=10V, T_C=75^{\circ}C$	-	52	A
	I_D	$V_{GS}=10V, T_C=100^{\circ}C$	-	45	A
Pulsed drain current ^①	I_{DM}	Pulsed; $t_p \leq 10 \mu s; T_C = 25^{\circ}C$;	-	256	A
Diode continuous current	I_S	$V_{GS}=0V, T_C=25^{\circ}C$	-	42	A
Diode pulse current	$I_{S,pulse}$	Pulsed; $t_p \leq 10 \mu s; T_C = 25^{\circ}C$;	-	168	A
Total power dissipation	P_D	$T_C=25^{\circ}C$	-	54	W
Total power dissipation	P_D	$T_A=25^{\circ}C$	-	3.3	W
Operating junction temperature	T_J		-55	175	$^{\circ}C$
Storage temperature	T_{STG}		-55	175	$^{\circ}C$

Single pulse avalanche energy	E_{AS}	$L=0.1mH, V_{GS}=10V, R_g=25\Omega,$	-	45	mJ
ESD level (HBM)	CLASS 1C				

● P-Channel Absolute Maximum Ratings ($T_A=25^\circ C$, unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Max.	Unit
Drain-source voltage	V_{DS}		-	-40	V
Gate-source voltage ^①	V_{GS}		-20	20	V
Continuous drain current	I_D	$V_{GS}=-10V, T_C=25^\circ C$	-	-61	A
	I_D	$V_{GS}=-10V, T_C=75^\circ C$	-	-50	A
	I_D	$V_{GS}=-10V, T_C=100^\circ C$	-	-43	A
Pulsed drain current ^①	I_{DM}	Pulsed; $t_p \leq 10 \mu s; T_C = 25^\circ C;$	-	-244	A
Diode continuous current	I_S	$V_{GS}=0V, T_C=25^\circ C$	-	-61	A
Diode pulse current	$I_{S,pulse}$	Pulsed; $t_p \leq 10 \mu s; T_C = 25^\circ C;$	-	-244	A
Total power dissipation	P_D	$T_C=25^\circ C$	-	79	W
Total power dissipation	P_D	$T_A=25^\circ C$	-	3.3	W
Operating junction temperature	T_J		-55	175	$^\circ C$
Storage temperature	T_{STG}		-55	175	$^\circ C$
Single pulse avalanche energy	E_{AS}	$L=0.1mH, V_{GS}=-10V, R_g=25\Omega,$	-	174	mJ
ESD level (HBM)	CLASS 2				

● Thermal Resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R_{thJC} (N-Channel)	-	-	2.8	$^\circ C/W$
Thermal resistance, junction - case	R_{thJC} (P-Channel)	-	-	1.9	$^\circ C/W$
Thermal resistance, junction - ambient ^②	R_{thJA}	-	-	45	$^\circ C/W$
Soldering temperature(total time<10s)	T_{sold}	-	-	260	$^\circ C$

● N-Channel Electronic Characteristics ($T_J=25^\circ C$, unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	40	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	2	2.7	4	V
Drain-source leakage current	I_{DSS}	$V_{GS}=0V, V_{DS}=40V$	-	-	1	μA
Gate- source leakage current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA

Static drain-source on resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=16A, T_j=25^{\circ}C$	-	6.4	7.7	mΩ
Forward transconductance	g_{FS}	$V_{DS}=5V, I_{SD}=10A$	-	11	-	S
Diode forward voltage	V_{FSD}	$V_{GS}=0V, I_{SD}=16A$	-	0.8	1.3	V

● N-Channel Dynamic Characteristics ($T_j=25^{\circ}C$, unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$f = 1MHz, V_{DS}=25V, V_{GS}=0V$	-	859	-	pF
Output capacitance	C_{oss}		-	277	-	pF
Reverse transfer capacitance	C_{rss}		-	19	-	pF
Gate resistance	R_g	$f = 1MHz$	-	2.1	-	Ω
Total gate charge	Q_g	$V_{DD}=25V, I_D=16A, V_{GS}=10V$	-	14.5	-	nC
Gate-source charge	Q_{gs}		-	2.8	-	nC
Gate-drain charge	Q_{gd}		-	5.2	-	nC
Turn-on delay time	$t_{D(on)}$	$V_{GS}=10V, V_{DS}=25V, R_G=3.3\Omega, I_D=16A$	-	5	-	ns
Turn-on rise time	t_r		-	10	-	ns
Turn-off delay time	$t_{D(off)}$		-	8	-	ns
Turn-off fall time	t_f		-	3	-	ns
Reverse recovery time	t_{rr}	$V_{DD}=25V, dI_S/dt = 100A/us, I_S=16A$	-	30	-	ns
Reverse recovery charge	Q_{rr}		-	21	-	nC

● P-Channel Electronic Characteristics ($T_j=25^{\circ}C$, unless otherwise specified)

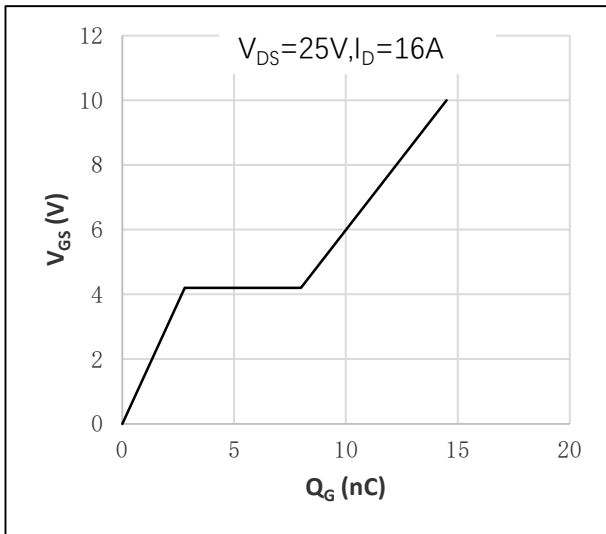
Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	BV_{DSS}	$V_{GS}=0V, I_D=-250\mu A$	-40	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.3	-2	-2.5	V
Drain-source leakage current	I_{DSS}	$V_{GS}=0V, V_{DS}=-40V$	-	-	-1	μA
Gate- source leakage current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	±100	nA
Static drain-source on resistance	$R_{DS(ON)}$	$V_{GS}=-10V, I_D=-16A, T_j=25^{\circ}C$	-	10.4	12.5	mΩ
		$V_{GS}=-4.5V, I_D=-9A, T_j=25^{\circ}C$	-	19	23	mΩ
Forward transconductance	g_{FS}	$V_{DS}=-5V, I_{SD}=-10A$	-	13	-	S
Diode forward voltage	V_{FSD}	$V_{GS}=0V, I_{SD}=-16A$	-	-0.8	-1.3	V

● P-Channel Dynamic Characteristics ($T_j=25^{\circ}\text{C}$, unless otherwise specified)

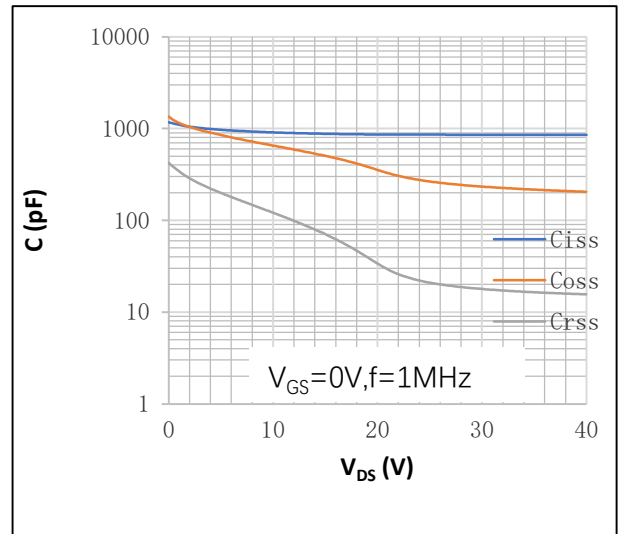
Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$f = 1\text{MHz}$, $V_{DS}=-25\text{V}$, $V_{GS}=0\text{V}$	-	2573	-	pF
Output capacitance	C_{oss}		-	544	-	pF
Reverse transfer capacitance	C_{rss}		-	39	-	pF
Gate resistance	R_g	$f = 1\text{MHz}$	-	5.2	-	Ω
Total gate charge	Q_g	$V_{DD} = -25\text{V}$, $I_D = -16\text{A}$, $V_{GS} = -10\text{V}$	-	39.5	-	nC
Total gate charge(-4.5V)	Q_g		-	19.8	-	nC
Gate-source charge	Q_{gs}		-	7.8	-	nC
Gate-drain charge	Q_{gd}		-	9.1	-	nC
Turn-on delay time	$t_{D(on)}$	$V_{GS}=-10\text{V}$, $V_{DS}=-25\text{V}$, $R_G=3.3\Omega$, $I_D=-16\text{A}$	-	15	-	ns
Turn-on rise time	t_r		-	9	-	ns
Turn-off delay time	$t_{D(off)}$		-	19	-	ns
Turn-off fall time	t_f		-	25	-	ns
Reverse recovery time	t_{rr}	$V_{DD}=-25\text{V}$, $dI_S/dt = -$ $100\text{A}/\mu\text{s}$, $I_S=-16\text{A}$	-	35	-	ns
Reverse recovery charge	Q_{rr}		-	28	-	nC

●N-Channel Characteristics Curve ($T_J=25^{\circ}\text{C}$, unless otherwise specified)

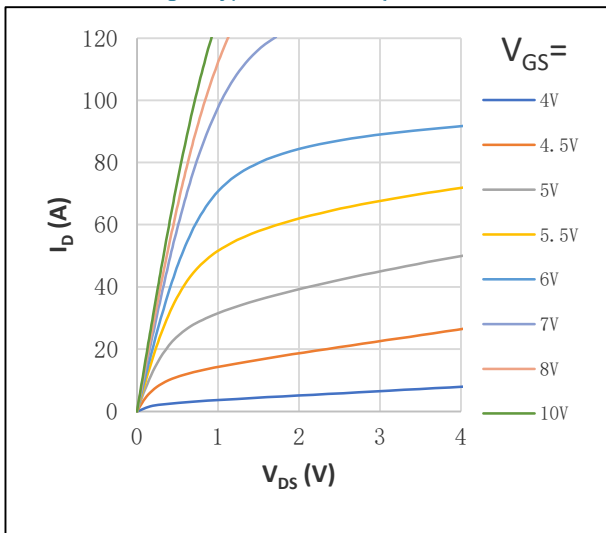
●Fig.1 Gate-source voltage as a function of gate charge;
Typical values; $T_J=25^{\circ}\text{C}$



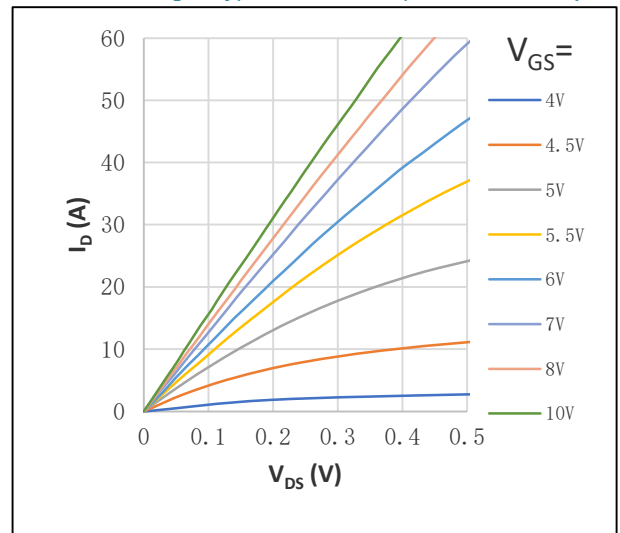
●Fig.2 Input, output and reverse transfer capacitances as a function of drain-source voltage; Typical values; $T_J=25^{\circ}\text{C}$



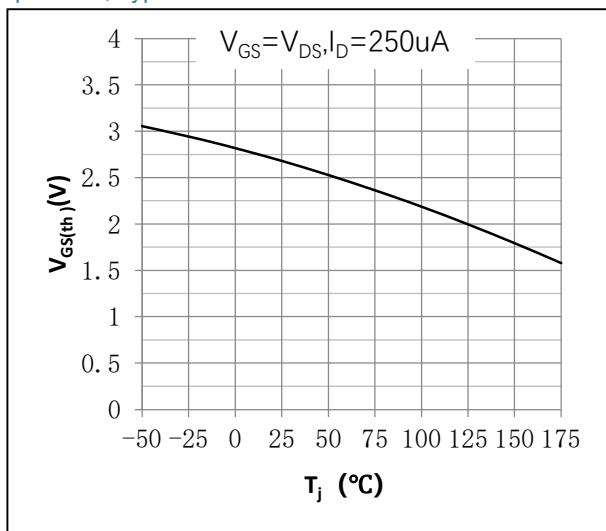
●Fig.3 Output characteristics: drain current as a function of drain-source voltage; Typical values; $T_J=25^{\circ}\text{C}$



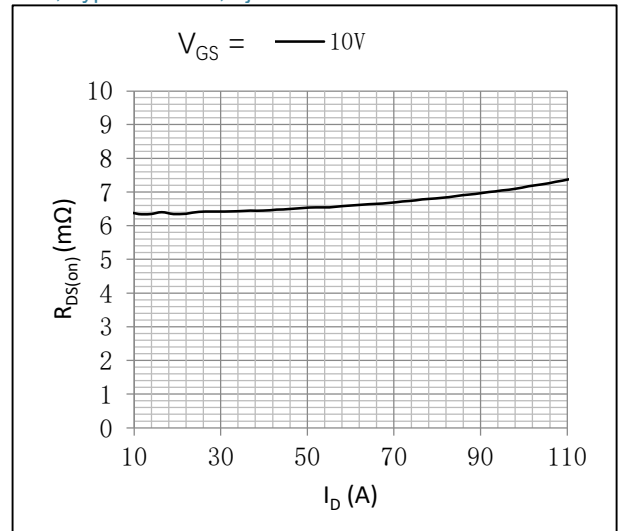
●Fig.4 Output characteristics: drain current as a function of drain-source voltage; Typical values; Expanded curve; $T_J=25^{\circ}\text{C}$



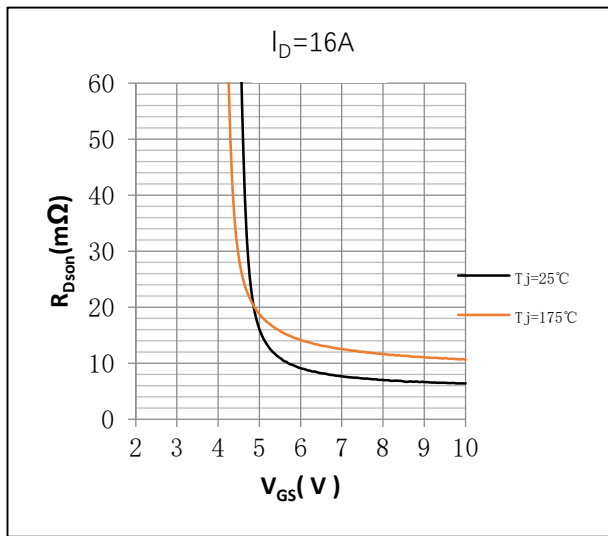
●Fig.5 Gate-source threshold voltage as a function of junction temperature; Typical values



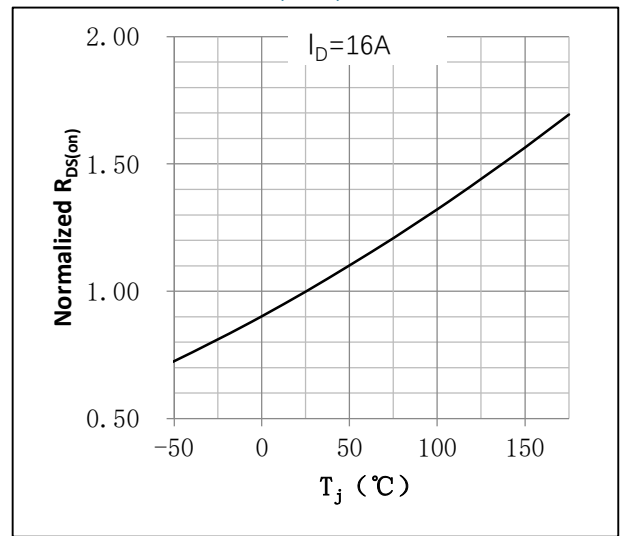
●Fig.6 Drain-source on-state resistance as a function of drain current; Typical values; $T_J=25^{\circ}\text{C}$



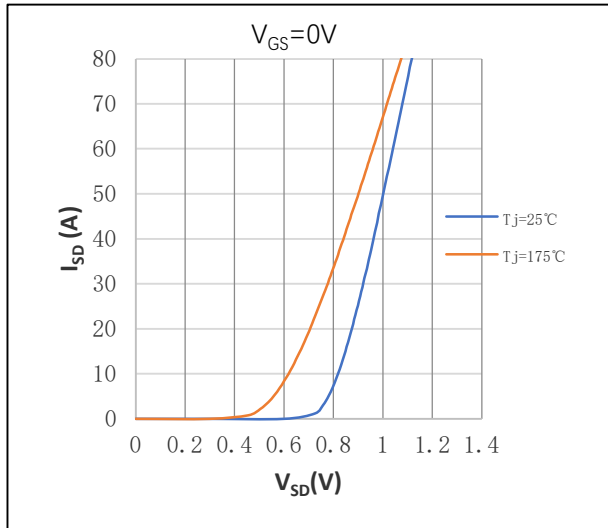
● Fig.7 Drain-source on-state resistance as a function of gate-source voltage; Typical values



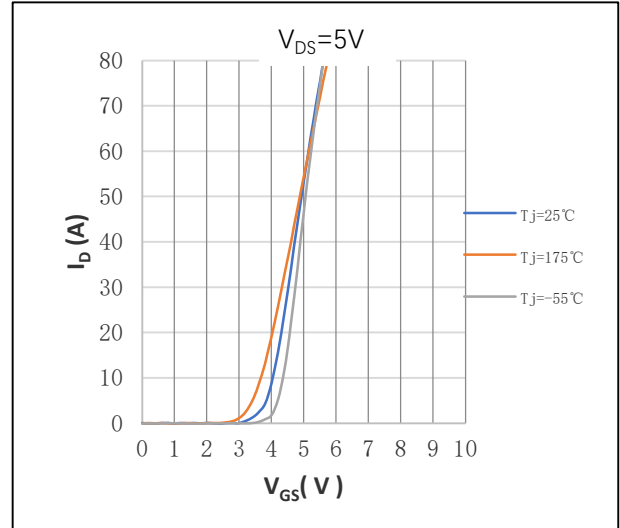
● Fig.8 Normalized drain-source on-state resistance factor as a function of junction temperature; Typical values Normalized On-Resistance = $R_{DS(on)}/R_{DS(on)}(25^{\circ}\text{C})$



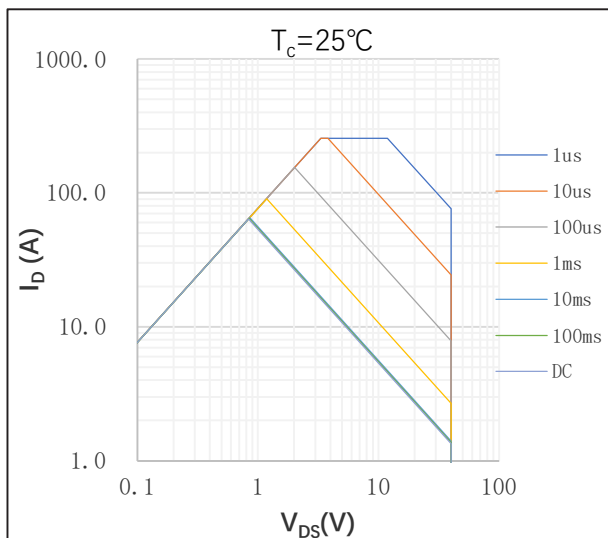
● Figure 9. Source (diode forward) current as a function of source-drain (diode forward) voltage; Typical values



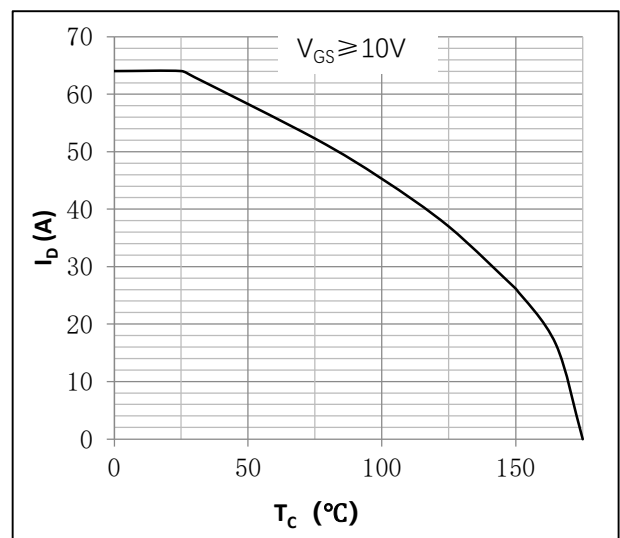
● Figure 10. Transfer characteristics: drain current as a function of gate-source voltage; Typical values



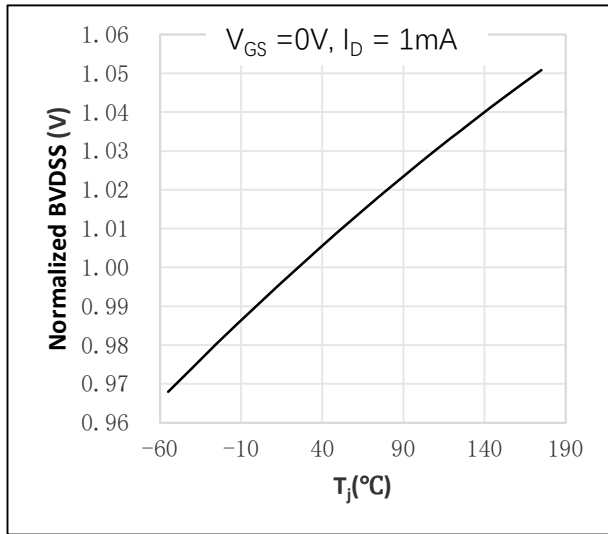
● Fig.11 Safe operating area: continuous and peak drain currents as a function of drain-source voltage; Calculative values



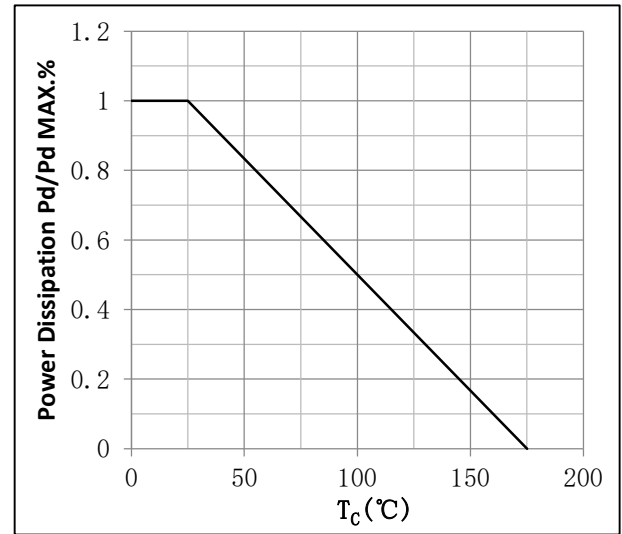
● Fig.12 Continuous drain current as a function of case temperature³; Calculative values



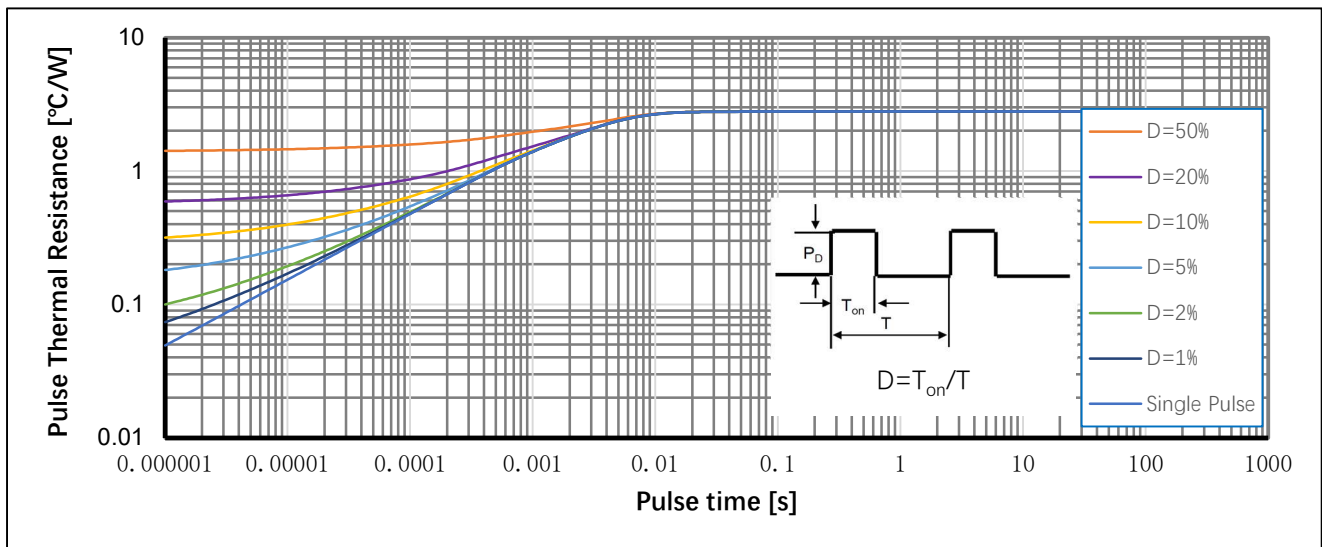
● Fig.13 Drain-source breakdown voltage as a function of junction temperature; Typical values



● Fig.14 Normalized total power dissipation as a function of case temperature; Calculative values Normalized Power Dissipation = $P_d/P_d(25^{\circ}C)$

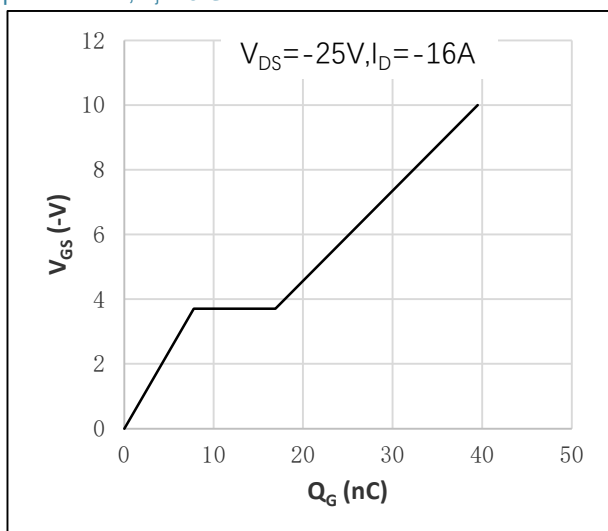


● Fig.15 Transient thermal impedance from junction to case as a function of pulse duration; max values

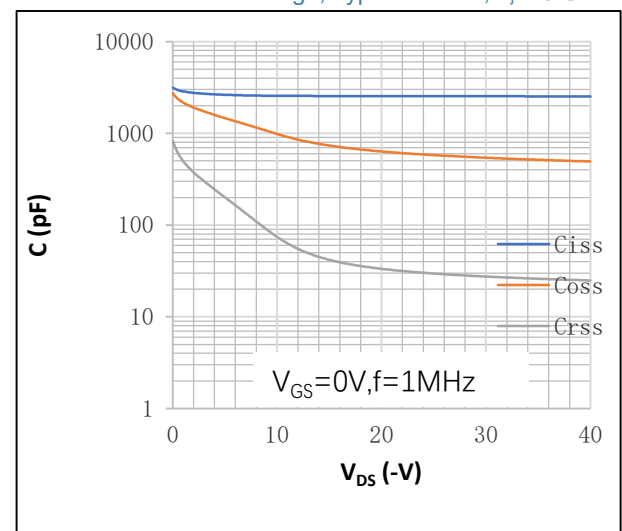


● P-Channel Characteristics Curve ($T_J = 25^{\circ}C$, unless otherwise specified)

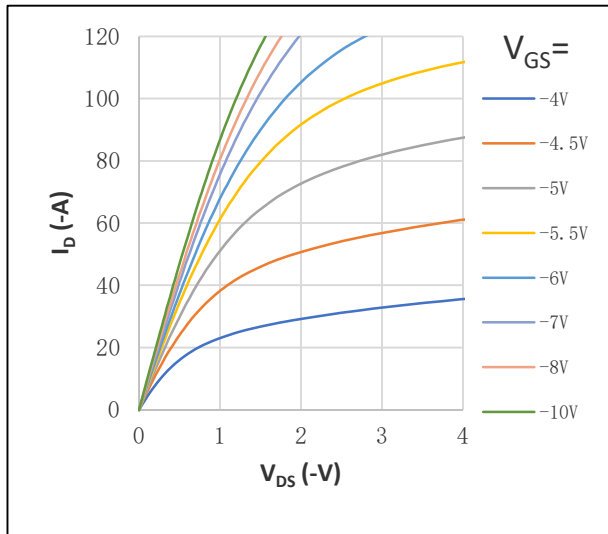
● Fig.1 Gate-source voltage as a function of gate charge; Typical values; $T_J = 25^{\circ}C$



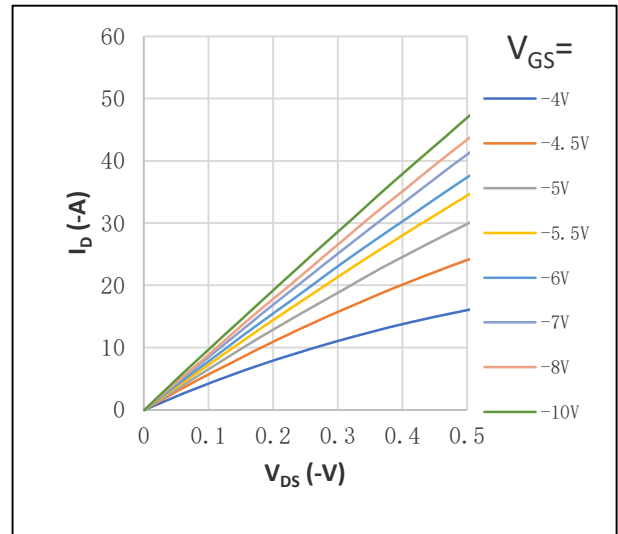
● Fig.2 Input, output and reverse transfer capacitances as a function of drain-source voltage; Typical values; $T_J = 25^{\circ}C$



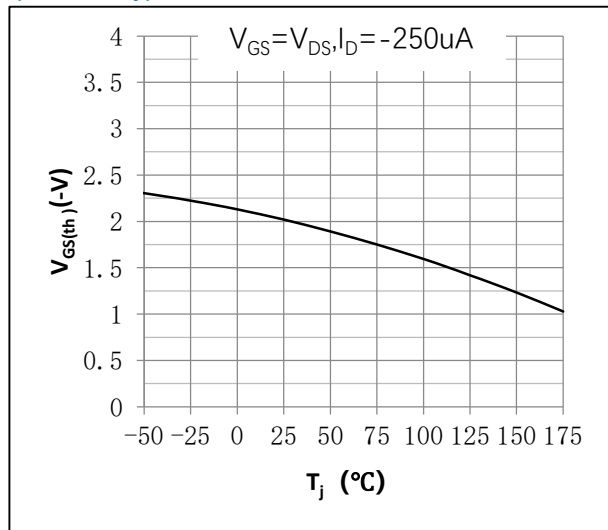
● Fig.3 Output characteristics: drain current as a function of drain-source voltage; Typical values: $T_j=25^\circ\text{C}$



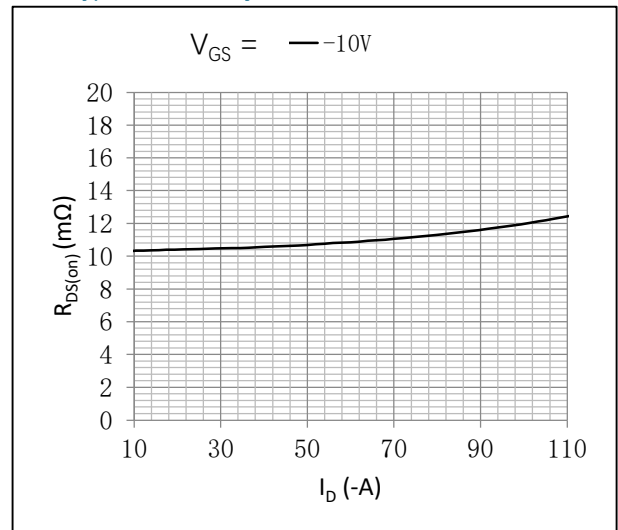
● Fig.4 Output characteristics: drain current as a function of drain-source voltage; Typical values: Expanded curve; $T_j=25^\circ\text{C}$



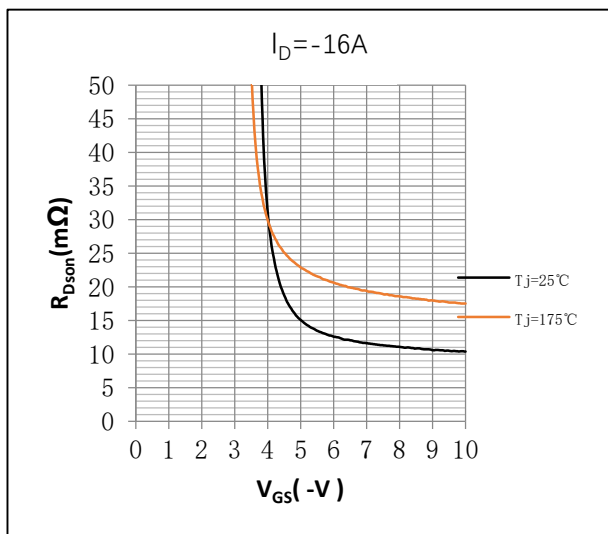
● Fig.5 Gate-source threshold voltage as a function of junction temperature; Typical values



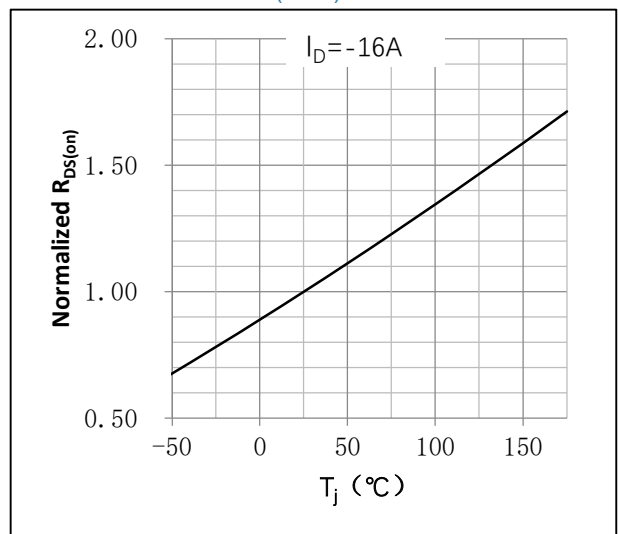
● Fig.6 Drain-source on-state resistance as a function of drain current; Typical values; $T_j=25^\circ\text{C}$



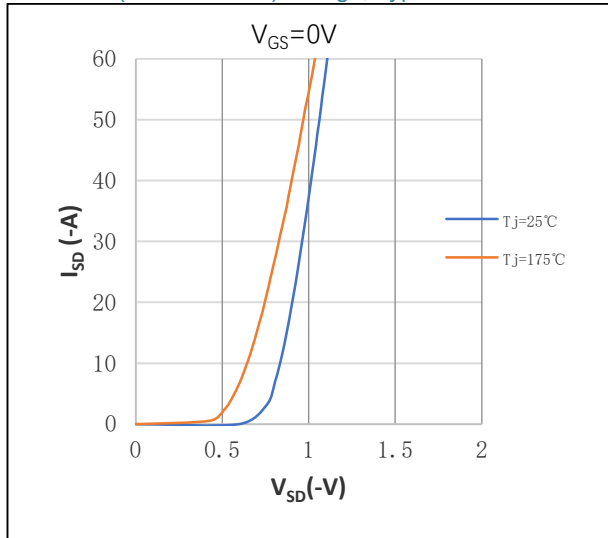
● Fig.7 Drain-source on-state resistance as a function of gate-source voltage; Typical values



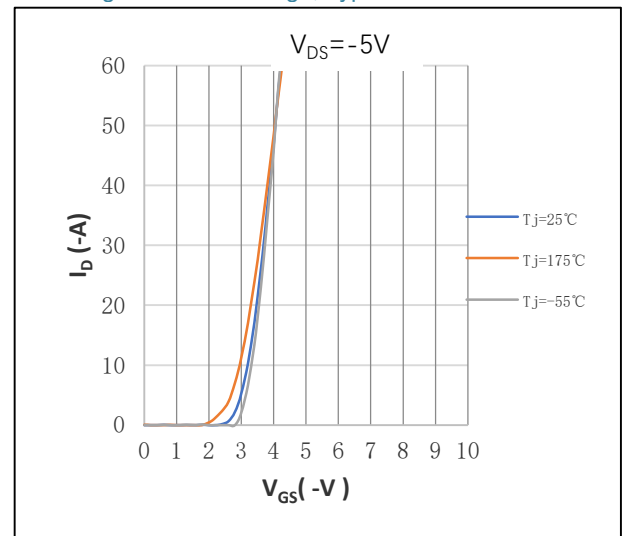
● Fig.8 Normalized drain-source on-state resistance factor as a function of junction temperature; Typical values Normalized On-Resistance= $R_{DS(on)}/R_{DS(on)}(25^\circ\text{C})$



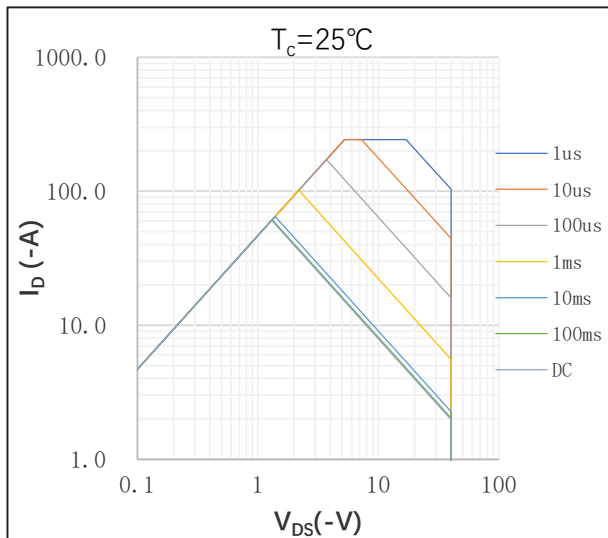
● Figure 9. Source (diode forward) current as a function of source-drain (diode forward) voltage; Typical values



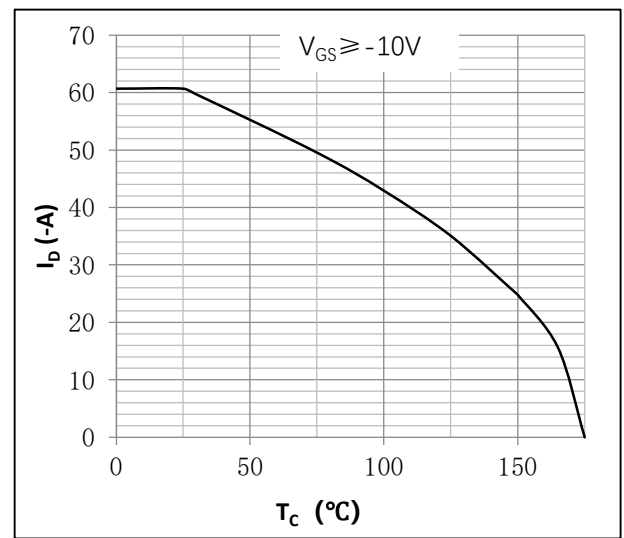
● Figure 10. Transfer characteristics: drain current as a function of gate-source voltage; Typical values



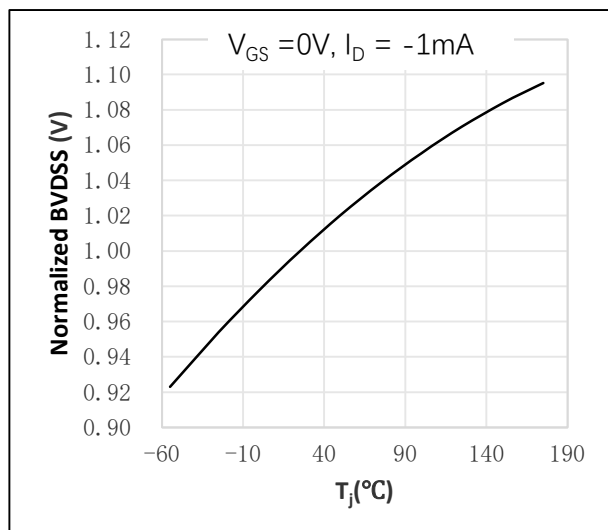
● Fig.11 Safe operating area: continuous and peak drain currents as a function of drain-source voltage; Calculative values



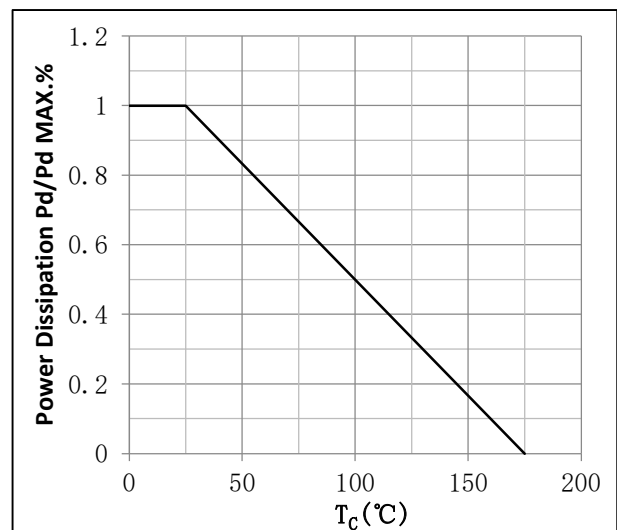
● Fig.12 Continuous drain current as a function of case temperature³; Calculative values



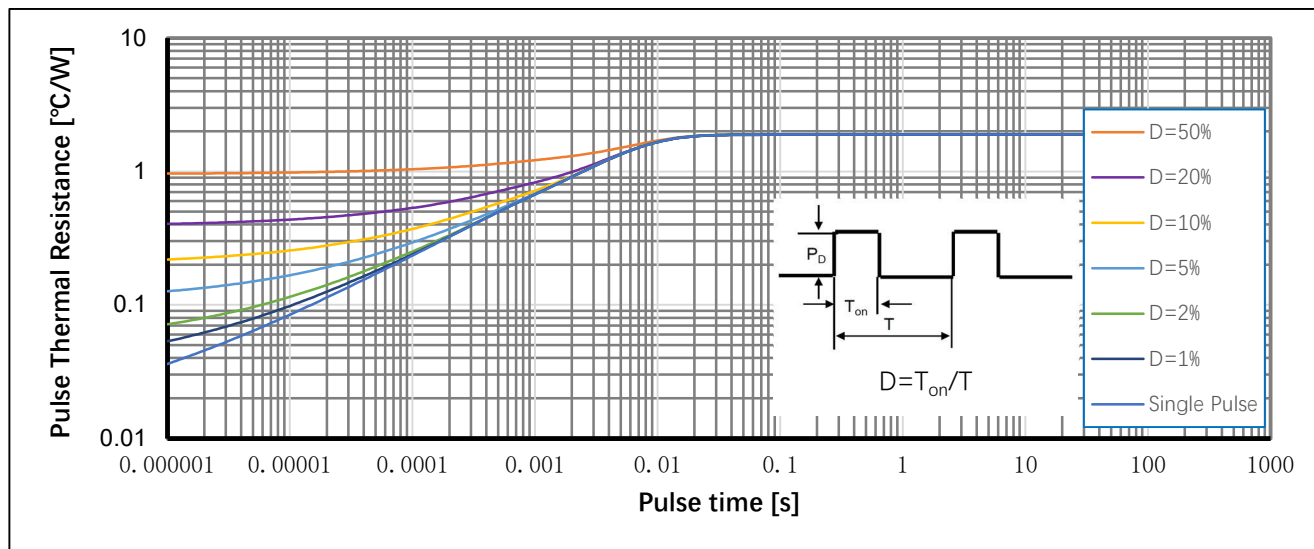
● Fig.13 Drain-source breakdown voltage as a function of junction temperature; Typical values



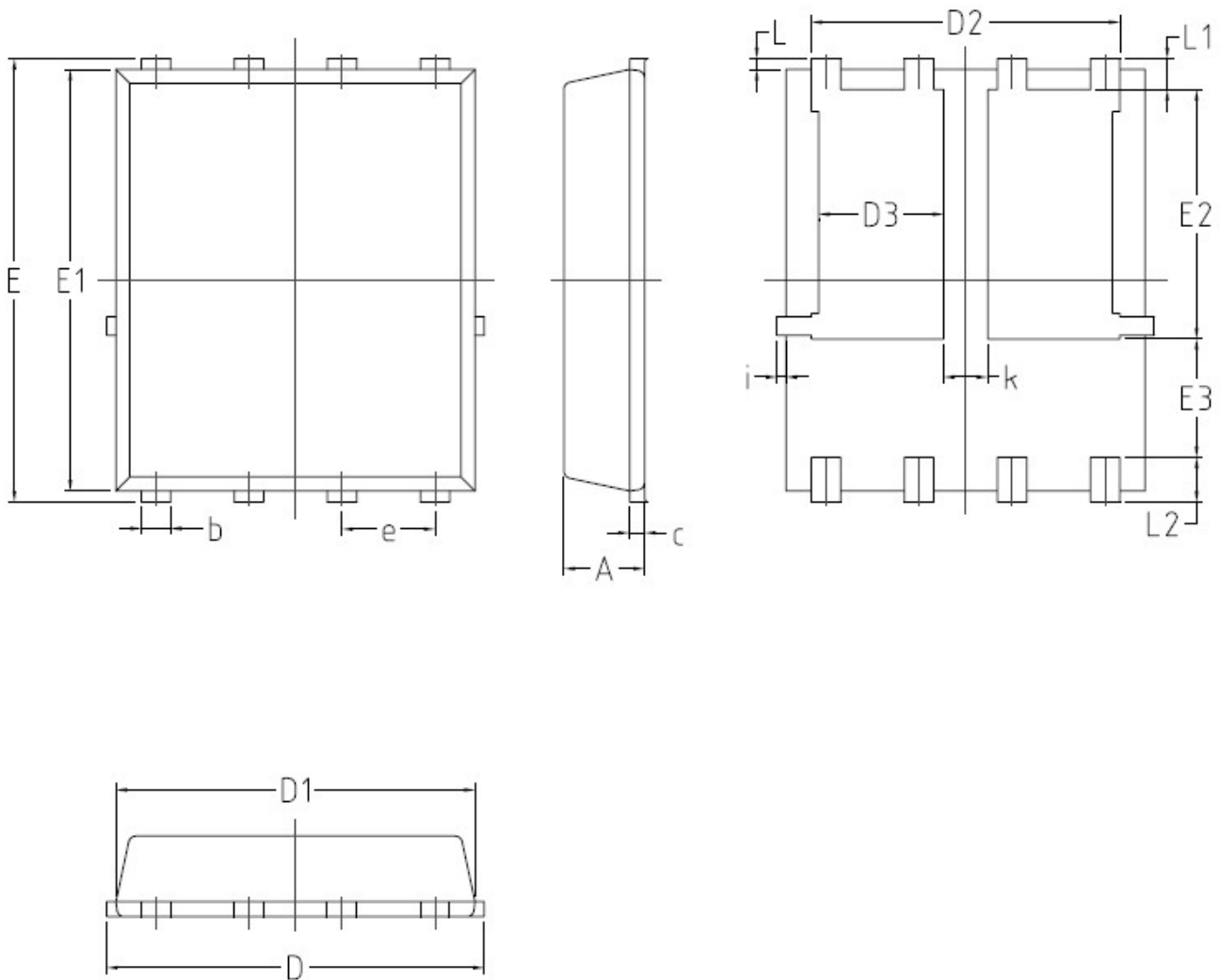
● Fig.14 Normalized total power dissipation as a function of case temperature; Calculative values Normalized Power Dissipation = $P_d/P_d(25^\circ\text{C})$



● Fig.15 Transient thermal impedance from junction to case as a function of pulse duration; max values



● Package Outline



SYMBOL	COMMON			
	MM		INCH	
	MIN.	MAX.	MIN.	MAX.
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.203 BSC		0.0080 BSC	
D	4.80	5.40	0.1890	0.2126
D1	4.80	5.00	0.1890	0.1969
D2	4.11	4.31	0.1620	0.1700
D3	1.60	1.80	0.0629	0.0708
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	3.30	3.50	0.1300	0.1378
E3	1.40	/	0.0551	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0019	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.71	0.0150	0.0280
i	/	0.18	/	0.0070
k	0.5	0.7	0.0197	0.0276

● Note

- ① Pulse : $V_{GS}=+20V/-20V$, Duty cycle=50%, $T_J=175^{\circ}C$, $t=1000$ hours; For DC, the following test conditions can be passed: $V_{GS}=+20V/-10V$, $T_J=175^{\circ}C$, $t=1000$ hours;
- ② Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;
- ③ Practically the current will be limited by PCB, thermal design and operating temperature. $V_{GS}=10V$ (N-channel)/
-10V(P-channel).

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● Revision History

Version	Date	Change
A	2025/10/17	New